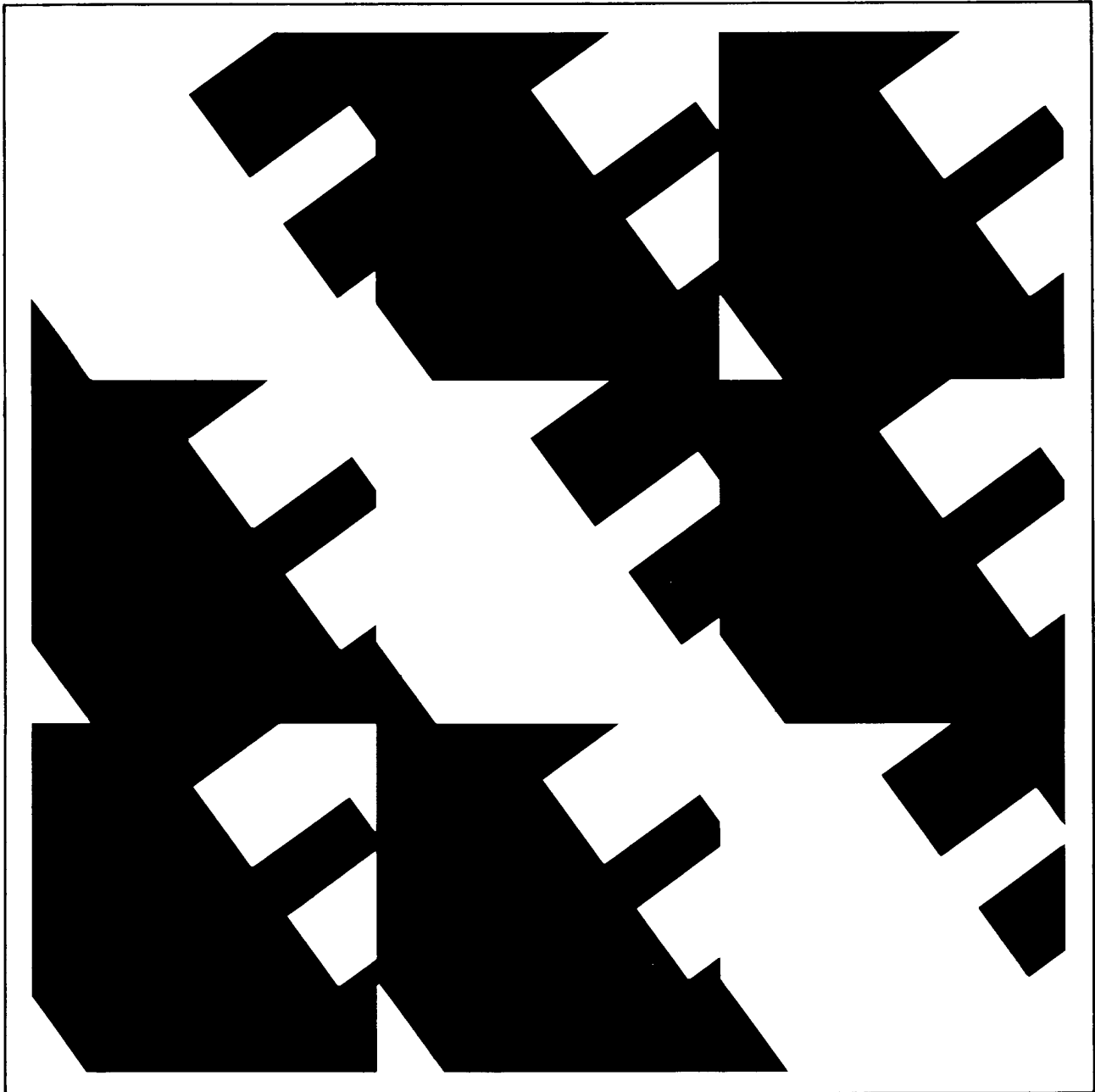


IEEE Trial-Use Recommended Practice for the Evaluation of the Impulse Voltage Capability of Insulation Systems for AC Electric Machinery Employing Form-Wound Stator Coils



IEEE Std 792



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Draft American National Standard

**IEEE Trial-Use Recommended Practice for the
Evaluation of the Impulse Voltage Capability of
Insulation Systems for AC Electric Machinery
Employing Form-Wound Stator Coils**

Sponsor
**Rotating Machinery Committee
of the
Power Engineering Society**

Approved September 10, 1987
IEEE Standards Board

Draft American National Standard

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Foreword

(This Foreword is not a part of IEEE Std 792, IEEE Trial-Use Recommended Practice for the Evaluation of the Impulse Voltage Capability of Insulation Systems for AC Electric Machinery Employing Form-Wound Stator Coils.)

This test procedure was developed by the Insulation Subcommittee of the Rotating Machinery Committee of the Power Engineering Society. It is intended to provide a means to evaluate the capability of an insulation system on a multi-turn coil to withstand steep fronted voltage surges. It is also designed to simulate aging of the machine so that relative comparisons between insulation systems can be made.

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